PH3030AL

N-channel TrenchMOS logic level FET

Rev. 03 — 12 January 2010

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing and consumer applications.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

1.3 Applications

- Consumer applications
- Desktop Voltage Regulator Module (VRM)
- Notebook Voltage Regulator Module (VRM)

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	-	30	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	<u>[1]</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	81	W
Dynamic	characteristics						
Q_{GD}	gate-drain charge	V_{GS} = 4.5 V; I_D = 10 A; V_{DS} = 12 V; see <u>Figure 14</u> and <u>15</u>		-	5.1	-	nC
Q _{G(tot)}	total gate charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \frac{\text{Figure } 14}{\text{Figure } 14}$		-	21	-	nC
Static ch	aracteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}$		-	2.19	3	mΩ

^[1] Continuous current is limited by package.



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol				
1	S	source		_				
2	S	source	mb	D				
3	S	source						
4	G	gate	[q]					
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S				
			SOT669 (LFPAK)					

3. Ordering information

Table 3. Ordering information

Type number	Package	ckage					
	Name	Description	Version				
PH3030AL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669				

4. Limiting values

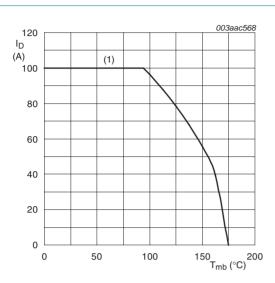
Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$		-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
V_{GS}	gate-source voltage			-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	[1]	-	96	Α
		$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \underline{\text{Figure 1}}$	<u>[1]</u>	-	100	Α
I_{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3		-	496	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	81	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dr	ain diode					
Is	source current	$T_{mb} = 25 ^{\circ}C;$	[1]	-	100	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	496	Α
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; V_{sup} ≤ 30 V; R_{GS} = 50 Ω; unclamped		-	75	mJ

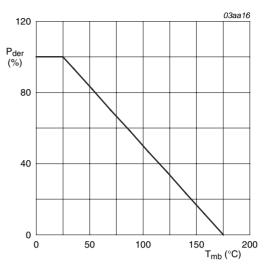
^[1] Continuous current is limited by package.

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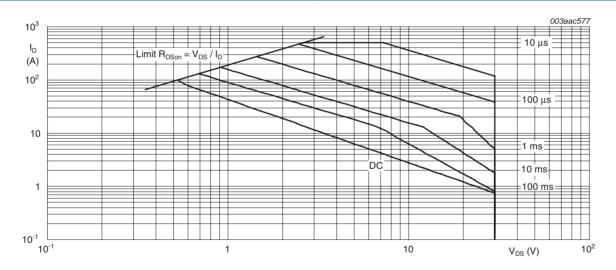
 $V_{GS} \ge 10 \text{ V}$; (1) Capped at 100 A due to package

Fig 1. Continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 T_{mb} = 25 °*C*; I_{DM} is single pulse (1) Capped at 100 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

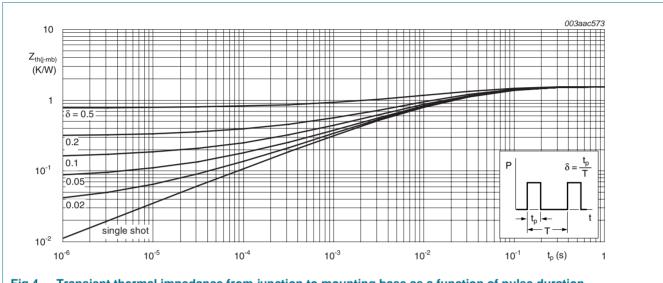
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5. Thermal characteristics

Thermal characteristics Table 5.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.91	1.5	K/W	



Transient thermal impedance from junction to mounting base as a function of pulse duration

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6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 20 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}; t_{av} = 100 \text{ ns}$	35	-	-	V
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	30	-	-	V
		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	27	-	-	V
$V_{GS(th)}$ gate-source threshold voltage		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 11</u> and <u>12</u>	1.3	1.7	2.15	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 150 °C; see <u>Figure 12</u>	0.65	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = -55 °C; see <u>Figure 12</u>	-	-	2.45	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
		V_{GS} = -16 V; V_{DS} = 0 V; T_j = 25 °C	-	-	100	nA
R _{DSon}	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	3.04	4.04	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C};$ see <u>Figure 13</u>	-	-	5.2	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	2.19	3	mΩ
R_G	gate resistance	f = 1 MHz	-	0.55	1.5	Ω
Dynamic (characteristics					
Q _{G(tot)}	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 14</u> and <u>15</u>	-	45.8	-	nC
		$I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V$	-	43	-	nC
		$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see <u>Figure 14</u>	-	21	-	nC
Q _{GS}	gate-source charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	7.02	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	see Figure 14 and 15	-	4.74	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	2.28	-	nC
Q_{GD}	gate-drain charge		-	5.1	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$V_{DS} = 12 \text{ V}$; see <u>Figure 14</u> and <u>15</u>	-	2.37	-	V
C _{iss}	input capacitance	V _{DS} = 12 V; V _{GS} = 0 V; f = 1 MHz;	-	2822	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	615	-	pF
C _{rss}	reverse transfer capacitance		-	260	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	34	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	58	-	ns
t _{d(off)}	turn-off delay time		-	50	-	ns
t _f	fall time			21	-	ns

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Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 17</u>	-	0.82	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	35	-	ns
Q_{r}	recovered charge	V _{DS} = 20 V	-	29	-	nC

[1] Tested to JEDEC standards where applicable.

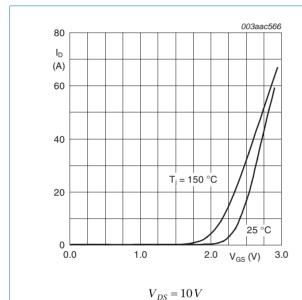


Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values

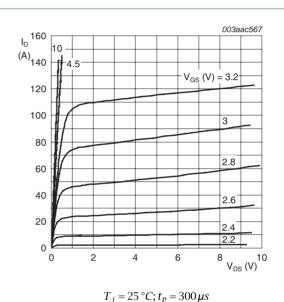


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

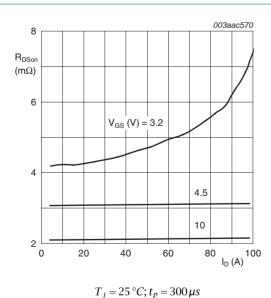
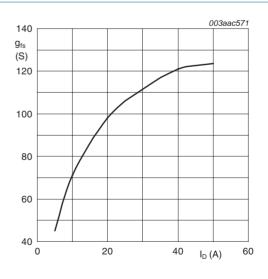


Fig 7. Drain-source on-state resistance as a function of drain current; typical values



 $T_j = 25 \,{}^{\circ}C; V_{DS} = 15 \, V$

Fig 8. Forward transconductance as a function of drain current; typical values

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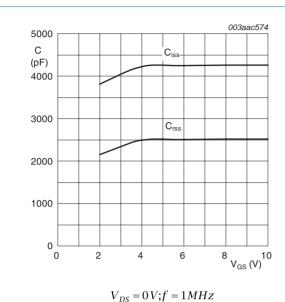
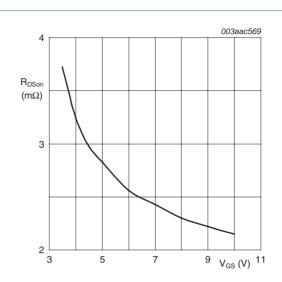
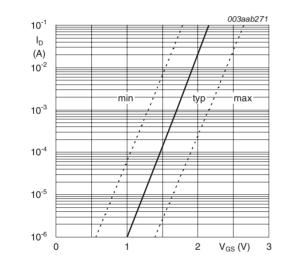


Fig 9. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



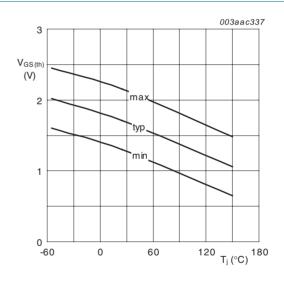
 $T_j = 25 \,^{\circ}C; I_D = 10A$

Fig 10. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $T_{j}=25\,^{\circ}C; V_{DS}=5\,V$ Fig 11. Sub-threshold drain current as a function of

gate-source voltage



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 12. Gate-source threshold voltage as a function of junction temperature

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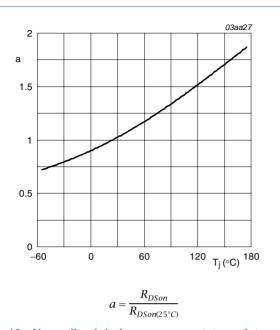


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

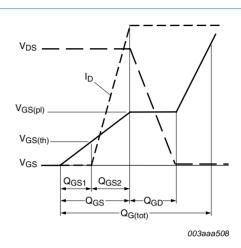


Fig 14. Gate charge waveform definitions

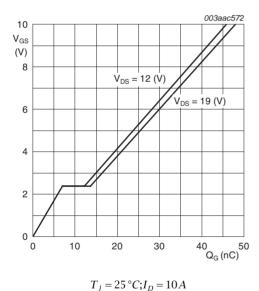
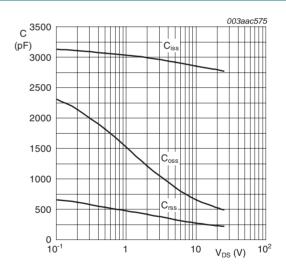


Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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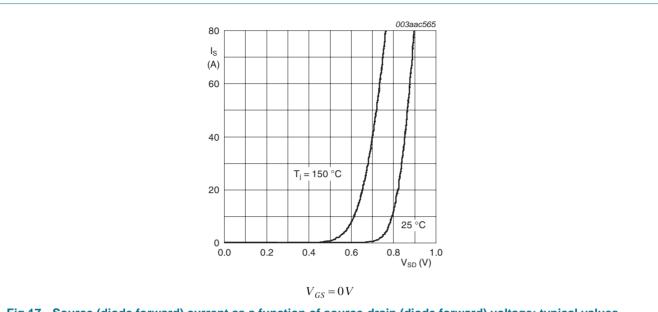
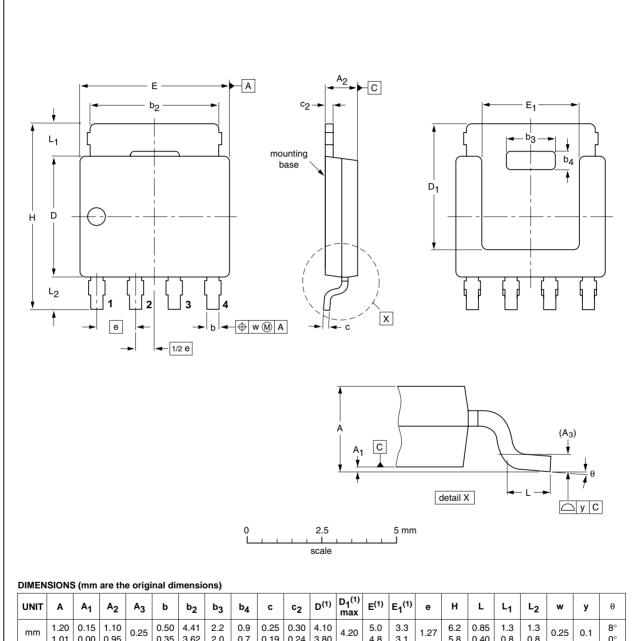


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UNIT	A	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	0.30 0.24	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT669		MO-235				04-10-13 06-03-16

Fig 18. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH3030AL_3	20100112	Product data sheet	-	PH3030AL_2
Modifications:	 Various cha 	anges to content.		
PH3030AL_2	20090121	Product data sheet	-	PH3030AL_1
PH3030AL_1	20080909	Preliminary data sheet	-	-

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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